



Initial Product/Process Change Notification

Document #: IPCN25729XD

Issue Date: 09 Sep 2024

Title of Change:	Wafer Fab Site Transfer from LA Semiconductor Idaho, United States to onsemi Bucheon, Korea for ESD and Surge Protection Products.	
Proposed First Ship date:	01 Dec 2025 or earlier if approved by customer	
Contact Information:	Contact your local onsemi Sales Office or bk8ph3_pe@onsemi.com or maya.abubakar@onsemi.com or jianhao.see@onsemi.com	
PCN Samples Contact:	Contact your local onsemi Sales Office. Sample requests are to be submitted no later than 30 days from the date of first notification, Initial PCN or Final PCN, for this change. Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements.	
Type of Notification:	This is an Initial Product/Process Change Notification (IPCN) sent to customers. An IPCN is an advance notification about an upcoming change and contains general information regarding the change details and devices affected. It also contains the preliminary reliability qualification plan. The completed qualification and characterization data will be included in the Final Product/Process Change Notification (FPCN). This IP.CN notification will be followed by a Final Product/Process Change Notification (FPCN) at least 90 days prior to implementation of the change. In case of questions, contact < PCN.Support@onsemi.com >	
Marking of Parts/ Traceability of Change:	Changed material can be identified by lot code	
Change Category:	Wafer Fab Change	
Change Sub-Category(s):	Manufacturing Site Transfer	
Sites Affected:		
onsemi Sites	External Foundry/Subcon Sites	
onsemi Bucheon, Korea	None	
Description and Purpose:		
onsemi would like to notify its customers of its intent to qualify our ESD and Surge Protection Products at our onsemi Bucheon, Korea wafer FAB. This qualification enables expanded capacity for this technology and ensures business continuity.		
Sample date/FPCN: August 2025		
Please work with your local sales team to provide the bridge quantity required until the production shipments from onsemi Bucheon site begin. The sales team will provide a quote for the bridge quantity order with an expectation that an NCNR PO is placed within 30 days of receipt of IPCN.		
onsemi plans to begin shipping onsemi Bucheon product 3 months after FPCN is issued. If more time is needed to qualify, discuss it with your local sales team.		
	From	To
Fab Site	LA Semiconductor Idaho, United States	onsemi Bucheon, Korea



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Qualification Plan:

QV DEVICE NAME: ESDR0502NMUTBG

PACKAGE: UDFN-6, 1.2x1.0

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=150°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta=150°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1@260°C	
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs

QV DEVICE NAME: SZCM1213A-04SO

PACKAGE: SC-74-6

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=150°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta=150°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1@260°C	
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs

QV DEVICE NAME: SZTVS4201MR6T1G

RMS: 97122

PACKAGE: TSOP6

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=150°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta=150°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @260°C	
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs



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QV DEVICE NAME: NUP4114UPXV6T1G

PACKAGE: SOT-563-6

Test	Specification	Condition	Interval
High Temperature Storage Life	JESD22-A103	Ta=150°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1@260°C	
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs

QV DEVICE NAME: SZESD9101P2T5G

PACKAGE: SOD-923

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=150°C, 100% max rated V	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1@260°C	
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs

QV DEVICE NAME: ESD9M5.0ST5G

RMS: 97093

PACKAGE: SOD923

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=150°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta=150°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @260°C	
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs



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QV DEVICE NAME: SZESD8704MTWTAG

PACKAGE: WDFNW-10 2.5x1.0

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=150°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta=150°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1@260°C	
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs

QV DEVICE NAME: ESD8008MUTAG

PACKAGE: UDFN-14, 5.5x1.5

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=150°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta=150°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1@260°C	
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs

QV DEVICE NAME: ESD10201MUT5G

RMS: 97034

PACKAGE: X3DFN

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=150°C, 100% max rated V	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @260°C	
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs



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QV DEVICE NAME: NIV2161MTTAG

PACKAGE: WDFN-10 3.5x2.0

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=150°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta=150°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1@260°C	
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs

QV DEVICE NAME: ESDL3552PFCT5G

PACKAGE: Molded CSP X4DFN-2 (0.6x0.3)

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=150°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta=150°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1@260°C	
Temperature Cycling	JESD22-A104	Ta= -40°C to +125°C	1550 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs

QV DEVICE NAME: EMI8043MUTAG

PACKAGE: XDFN-16

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=150°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta=150°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1@260°C	
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs



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QV DEVICE NAME: SZMG2040MUTAG

PACKAGE: UDFN-18, 5.5x1.5

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=150°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta=150°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1@260°C	
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs

QV DEVICE NAME: ESD7321MUT5G

RMS: S94408

PACKAGE: X3DFN

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=150°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta=150°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1@260°C	
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs

QV DEVICE NAME: SZESD7205DT5G

PACKAGE: SOT723

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=150°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta=150°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1@260°C	
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs



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QV DEVICE NAME: SZESD7205WTT1G

PACKAGE: SC70

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=150°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta=150°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1@260°C	
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs

QV DEVICE NAME: SZESD7361XV2T1G

PACKAGE: SOD-523

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=150°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta=150°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1@260°C	
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs

QV DEVICE NAME: SZESD7241MXWT5G

PACKAGE: X2DFNW-2, 1.0x0.6

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=150°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta=150°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1@260°C	
Temperature Cycling	JESD22-A104	Ta= -55°C to +150°C	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs



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QV DEVICE NAME: SESD5111PFCT5G

RMS: 97040

PACKAGE: X4DFN

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=150°C, 100% max rated V	1008 hrs
High Temperature Storage Life	JESD22-A103	Ta=150°C	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @260°C	
Temperature Cycling	JESD22-A104	Ta= -40°C to +125°C	1000 cyc
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs
Unbiased Highly Accelerated Stress Test	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs

QV DEVICE NAME: ESD8011MUT5G

RMS: 97108

PACKAGE: X3DFN

Test	Specification	Condition	Interval
High Temperature Reverse Bias	JESD22-A108	Ta=150°C, 100% max rated V	1008 hrs
Preconditioning	J-STD-020 JESD-A113	MSL 1 @260°C	
Highly Accelerated Stress Test	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs

Estimated date for qualification completion: **31 July 2025**

List of Affected Parts:

Note: Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the **PCN Customized Portal**.

Part Number	Qualification Vehicle
ESDR0502NMUTBG	ESDR0502NMUTBG
ESDR0502NMUTAG	ESDR0502NMUTBG
NUP2114UCMR6T1G	SZCM1213A-04SO, SZTVS4201MR6T1G
NUP4114HMR6T1G	SZCM1213A-04SO, SZTVS4201MR6T1G
NUP3115UPMUTAG	ESDR0502NMUTBG
CM1213A-04SO	SZCM1213A-04SO
NUP4114UCLW1T2G	SZCM1213A-04SO
CM1293A-04SO	SZCM1213A-04SO
SCM1293A-04SO	SZCM1213A-04SO



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NUP4114UCW1T2G	SZCM1213A-04SO
NUP4114UPXV6T2G	ESDR0502NMUTBG, NUP4114UPXV6T1G
NUP2114UPXV5T1G	ESDR0502NMUTBG, NUP4114UPXV6T1G
NUP4114UPXV6T1G	ESDR0502NMUTBG, NUP4114UPXV6T1G
ESD9101P2T5G	SZESD9101P2T5G, ESD9M5.0ST5G
ESD8708MUTAG	SZESD8704MTWTAG, ESD8008MUTAG
ESD8704MUTAG	SZESD8704MTWTAG, ESD8008MUTAG
ESD7241N2T5G	SZESD7241MXWT5G
NIS1161MTTAG	ESD10201MUT5G, NIV2161MTTAG
ESDL3552BPFC5G	ESDL3552PFCT5G
ESDL3552PFCT5G	ESDL3552PFCT5G
EMI8041MUTAG	EMI8043MUTAG
EMI8143MUTAG	EMI8043MUTAG
EMI8042MUTAG	EMI8043MUTAG
EMI8142MUTAG	EMI8043MUTAG
EMI8141MUTAG	EMI8043MUTAG
EMI8041BMUTAG	EMI8043MUTAG
EMI8043MUTAG	EMI8043MUTAG
ESD8008MUTAG	ESD8008MUTAG
ESD7008MUTAG	SZMG2040MUTAG
ESD7016MUTAG	SZMG2040MUTAG
MG2040MUTAG	SZMG2040MUTAG
ESD7004MUTAG	SZMG2040MUTAG
ESDR0524SMUTAG	SZMG2040MUTAG
ESDR0524PMUTAG	SZMG2040MUTAG
ESD7104MUTAG	SZMG2040MUTAG
ESD8006MUTAG	ESD8008MUTAG
SESD8008MUTAG	ESD8008MUTAG
ESD7421N2T5G	ESD10201MUT5G, ESD7321MUT5G
ESD7002WTT1G	ESD10201MUT5G, SZESD7205WTT1G
ESD7L5.0DT5G	ESD9M5.0ST5G, SZESD7205DT5G
ESD7M5.0DT5G	ESD9M5.0ST5G, SZESD7205DT5G
ESDR0502BT1G	ESD9M5.0ST5G, SZESD7205WTT1G
ESD8551N2T5G	ESD8011MUT5G, ESD8008MUTAG, SZESD7241MXWT5G



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ESD8351XV2T1G	ESD8011MUT5G, ESD8008MUTAG, SZESD7361XV2T1G
ESD7504MUTAG	SESD5111PFCT5G, ESD8008MUTAG
ESD8104MUTAG	SESD5111PFCT5G, ESD8008MUTAG
ESD7551N2T5G	SZESD7205DT5G, SZESD7205WTT1G, SZESD7241MXWT5G
ESD7351HT1G	SZESD7205DT5G, SZESD7205WTT1G, SZESD7361XV2T1G
ESD7351XV2T1G	SZESD7205DT5G, SZESD7205WTT1G, SZESD7361XV2T1G